



Laboratoria De Nayer v.z.w.
Department of Electronics
Section E.M.C.

Jan De Nayerlaan 9
B-2860 Sint-Katelijne-Waver

Photo's test setup	
Product	DS RFID
LDN Number	LDN3918
Date of issue	2019-02-11
Standard	FCC part 15 subpart C
EMC report	PCC-RAD-4885

The test report may not be reproduced, unless as a complete packet, without written agreement of Laboratoria De Nayer v.z.w.
The results refer to the described sample or equipment under test only.
Neither the accredited status of Laboratoria De Nayer v.z.w., nor this test report implies that the sample or equipment under test is approved by BELAC or any other establishment.
In case the customer wants to refer to his appeal to our accredited laboratories, he will use the following orequivalent sentence: "Tested by Laboratoria De Nayer, E.M.C.department, accredited by BELAC for EMC-immunity and EMC-emission under registration number 041-T".

photo : conducted emission set-up (0.15-30MHz)

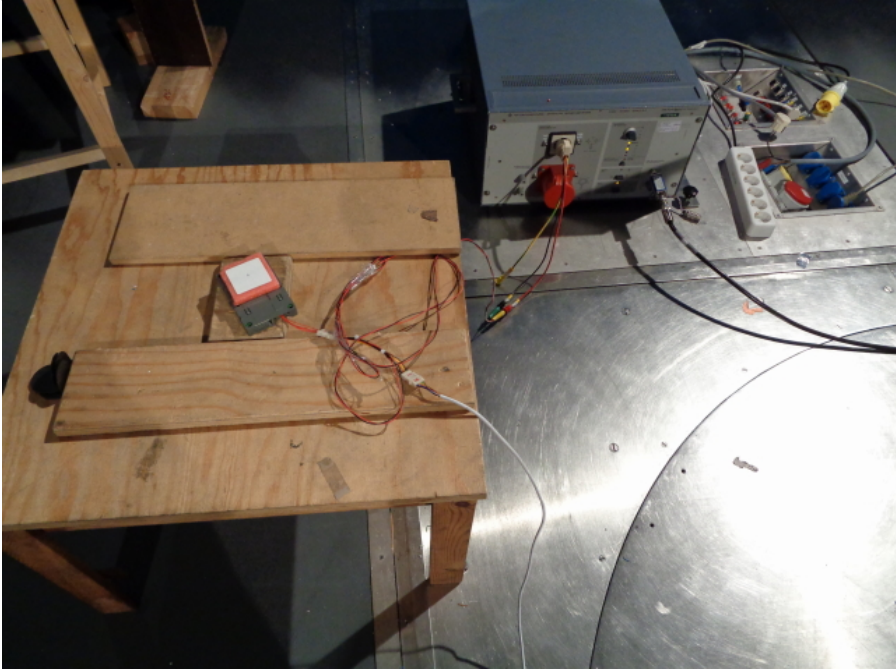


photo 2: radiated emission set-up (9k-30MHz)

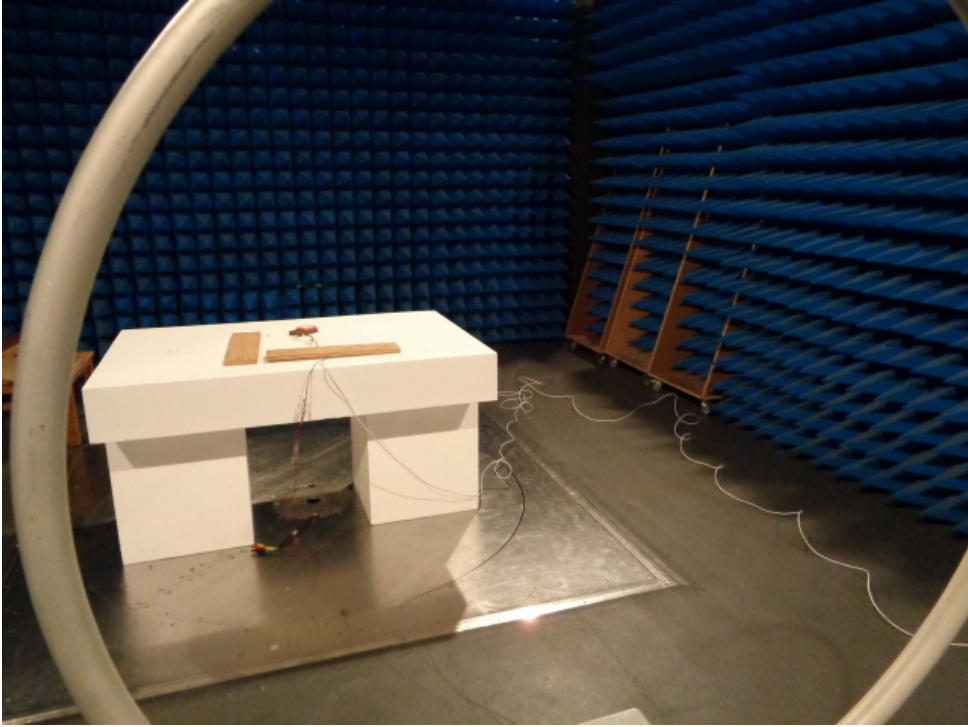


Photo : radiates emission (30-200MHz)

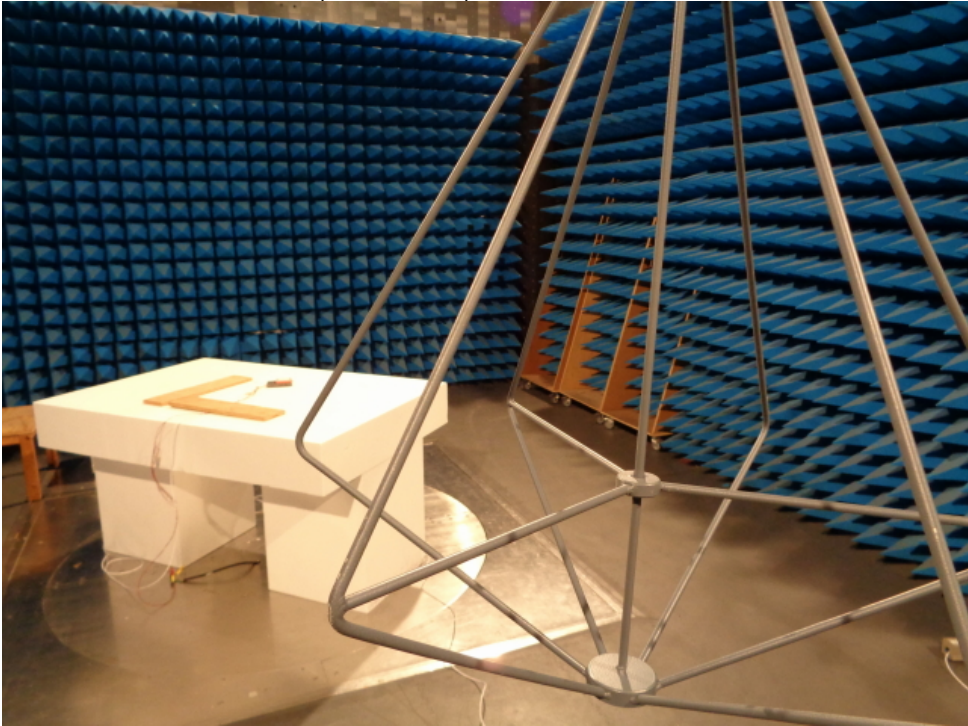


Photo : radiates emission (200-1000MHz)

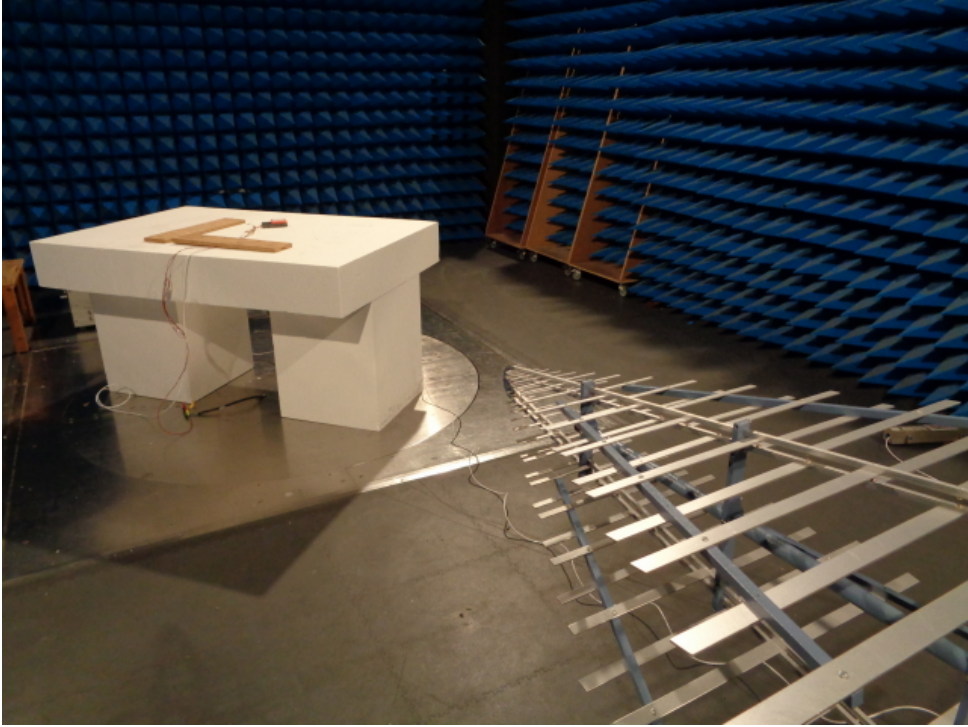


Photo : EUT in thermal chamber

